

REMARKS

The above amendments to the above-captioned application along with the following remarks are being submitted as a full and complete response to the Office Action dated April 18, 2008. In view of the above amendments and the following remarks, the Examiner is respectfully requested to give due reconsideration to this application, to indicate the allowability of the claims, and to pass this case to issue.

Status of the Claims

As outlined above, claims 1 and 4-6 stand for consideration in this application, wherein claim 1 is being amended. Claims 7-22 stand withdrawn from consideration in this application. All amendments to the application are fully supported therein, including Fig. 5. Applicants hereby submit that no new matter is being introduced into the application through the submission of this response.

Prior Art Rejections

35 U.S.C. §102(b) Rejection

Each of claims 1, 5, and 6 was rejected under 35 U.S.C. §102(b) as being anticipated by Doi (JP 2000-347217). Applicants respectfully traverse this rejection for the reasons set forth below.

According to the M.P.E.P. §2131, a claim is anticipated under 35 U.S.C. §102 (a), (b), and (e) only if each and every element as set forth in the claim is found, either expressly or inherently described, in a single prior art reference.

Claim 1

In a display device as recited in claim 1, at least one upper-layer film is formed above a film to be corrected at the correction portion and overlaps the correction portion. The correction is applied to the film to be corrected while the upper-layer film remains at a region which overlaps the correction portion. As illustrated in Fig. 5, for example, a short circuit defect DF, which is the collection portion, is removed while leaving the insulation film PAS, which overlaps the portion, from which the short circuit defect DF existed. (See page 19, line 13-17 of the specification.

In contrast, Doi shows that in order to solve the short circuit between the picture element electrode 5 and a common signal wiring 3 or a scanning wiring 2, a pinhole or short-

circuit defect part 12 is isolated from a picture element electrode 5 by removing a picture element electrode portion 13 around the short-circuit defect part 12 through irradiation with a laser from the picture element electrode side. (See paragraph [0009], [0028], [0032] and Fig. 4.) However, Doi does not show or suggest that correction is applied to a film including the picture element electrode 5 while the removed picture element electrode portion 13 is overlapped with any layer.

Therefore, Doi does not show every element recited in claim 1. Accordingly, claim 1 is not anticipated by Doi.

Claims 4-5

As to dependent claims 4-5, the arguments set forth above with respect to independent claim 1 are equally applicable here. The corresponding base claim being allowable, claims 4-5 must also be allowable.

35 U.S.C. §103(a) Rejection

Claim 4 was rejected under 35 U.S.C. §103(a) as being allegedly unpatentable over Doi in view of Liu et al. (U.S. Pat. No. 5,518,956). Applicants respectfully traverse this rejection for the reasons set forth below.

As set forth above, Doi fails to teach all the elements recited in claim 1, from which claim 4 depends. The secondary reference of Liu fails to provide any disclosure, teaching or suggestion that makes up for the deficiencies in Doi. Therefore, at the time the invention was made, one of ordinary skill in the art could not and would not achieve all the features as recited in claim 1, from which claim 4 depends.

Accordingly, claim 4 is not obvious in view of all the prior art cited.

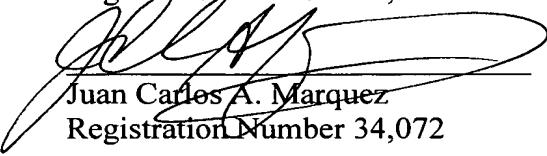
Conclusion

In light of the above Amendments and Remarks, Applicants respectfully request early and favorable action with regard to the present application, and a Notice of Allowance for all pending claims is earnestly solicited.

Favorable reconsideration of this application as amended is respectfully solicited. Should there be any outstanding issues requiring discussion that would further the prosecution and allowance of the above-captioned application, the Examiner is invited to contact the Applicants' undersigned representative at the address and phone number indicated below.

Respectfully submitted,

Stanley P. Fisher
Registration Number 24,344



Juan Carlos A. Marquez
Registration Number 34,072

REED SMITH LLP
3110 Fairview Park Drive
Suite 1400
Falls Church, Virginia 22042
(703) 641-4200

August 6, 2008
SPF/JCM/YOM